

PSMN6R0-30YLD

N-channel 30 V, 6.0 m Ω logic level MOSFET in LFPAK56 using NextPowerS3 Technology

10 February 2014

Product data sheet

1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

2. Features and benefits

- Ultra low Q_G, Q_{GD} and Q_{OSS} for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery; s-factor > 1
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1 μA leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, gualified to 175 °C
- Wave solderable; exposed leads for optimal visual solder inspection

3. Applications

- On-board DC-to-DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- Brushed and brushless motor control

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C	-	-	30	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 10 V; <u>Fig. 2</u>	-	-	66	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 1</u>	-	-	47	W





Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Tj	junction temperature		-55	-	175	°C
Static chara	acteristics			'		
R _{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 15 A; T_j = 25 °C; Fig. 10	-	6.7	8.35	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ Fig. 10	-	5	6	mΩ
Dynamic ch	naracteristics		,			
Q_{GD}	gate-drain charge	V _{GS} = 4.5 V; I _D = 15 A; V _{DS} = 15 V; Fig. 12; Fig. 13	-	1.8	-	nC
Q _{G(tot)}	total gate charge	V _{GS} = 4.5 V; I _D = 15 A; V _{DS} = 15 V; Fig. 12; Fig. 13	-	6.5	-	nC
Source-drai	in diode		'	'	'	
S	softness factor	I_S = 15 A; V_{GS} = 0 V; dI_S/dt = -100 A/ μ s; V_{DS} = 15 V; <u>Fig. 16</u>	-	1.2	-	

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source	mb	D L
2	S	source	<u> </u>	
3	S	source	q	G_U: 4
4	G	gate	טַ טַ טַ טַ	mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4 LFPAK56; Power- SO8 (SOT669)	

6. Ordering information

Table 3. Ordering information

Type number	Package	Package Package				
	Name	Description	Version			
PSMN6R0-30YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56; Power-SO8); 4 leads	SOT669			

7. Marking

Table 4. Marking codes

Type number		Marking code	
PSMN6R0-30YLD		6D030L	
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8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C		-	30	V
V_{DGR}	drain-gate voltage	$25 \text{ °C} \le T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V_{GS}	gate-source voltage			-20	20	V
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 1</u>		-	47	W
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; <u>Fig. 2</u>		-	66	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; <u>Fig. 2</u>		-	46	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 \text{ °C}$; Fig. 3		-	263	Α
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
T _{sld(M)}	peak soldering temperature			-	260	°C
V _{ESD}	electrostatic discharge voltage	НВМ		250	-	V
Source-dra	in diode				'	
Is	source current	T _{mb} = 25 °C		-	39	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 \text{ °C}$		-	263	Α
Avalanche	ruggedness			,		
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 15 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω; unclamped; t_p = 158 μs	[1]	-	46	mJ

^[1] Protected by 100% test

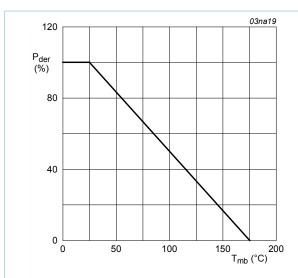


Fig. 1. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

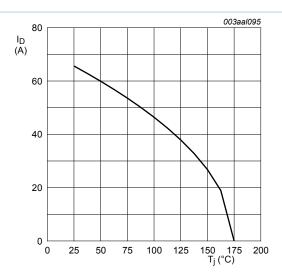


Fig. 2. Continuous drain current as a function of mounting base temperature

$$V_{GS} \ge 10V$$

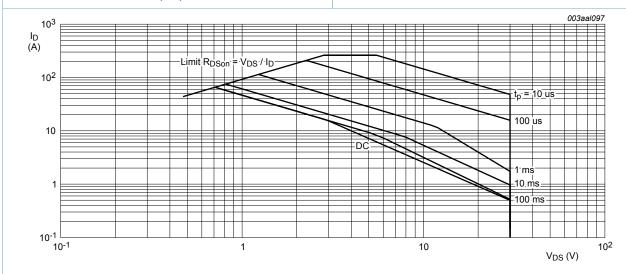


Fig. 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

 $T_{mb} = 25^{\circ}C$; I_{DM} is a single pulse

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 4	-	3	3.22	K/W

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-a)}	thermal resistance	Fig. 5	-	50	-	K/W
	from junction to ambient	<u>Fig. 6</u>	-	125	-	K/W

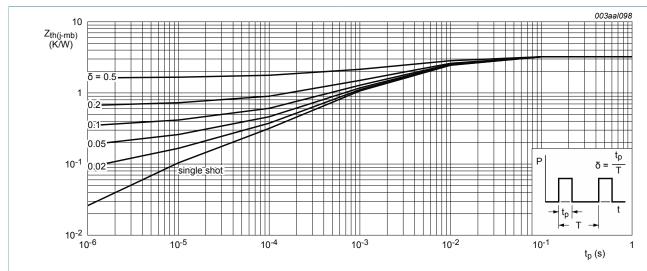


Fig. 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

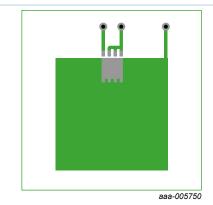


Fig. 5. PCB layout for thermal resistance junction to ambient 1" square pad; FR4 Board; 2oz copper

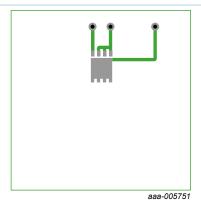


Fig. 6. PCB layout for thermal resistance junction to ambient minimum footprint; FR4 Board; 2oz copper

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static characteristics							
V _{(BR)DSS}	` '	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$		30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$		27	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$		1.2	1.83	2.2	V

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$\Delta V_{GS(th)}/\Delta T$	gate-source threshold voltage variation with temperature	25 °C ≤ T _j ≤ 150 °C	-	-4	-	mV/K
I _{DSS}	drain leakage current	$V_{DS} = 24 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	1	μΑ
		V _{DS} = 24 V; V _{GS} = 0 V; T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 16 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nA
		V _{GS} = -16 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ Fig. 10	-	6.7	8.35	mΩ
		V _{GS} = 4.5 V; I _D = 15 A; T _j = 150 °C; Fig. 11; Fig. 10	-	-	13.8	mΩ
	V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; <u>Fig. 10</u>	-	5	6	mΩ	
	V_{GS} = 10 V; I_D = 15 A; T_j = 150 °C; Fig. 11; Fig. 10	-	-	9.9	mΩ	
R_G	gate resistance	f = 1 MHz	-	2.36	-	Ω
Dynamic ch	aracteristics					
Q _{G(tot)} total gate charge	I _D = 15 A; V _{DS} = 15 V; V _{GS} = 10 V; Fig. 12; Fig. 13	-	13.7	-	nC	
		I _D = 15 A; V _{DS} = 15 V; V _{GS} = 4.5 V; Fig. 12; Fig. 13	-	6.5	-	nC
		I _D = 0 A; V _{DS} = 0 V; V _{GS} = 10 V	-	12.2	-	nC
Q_{GS}	gate-source charge	I _D = 15 A; V _{DS} = 15 V; V _{GS} = 4.5 V;	-	1.7	-	nC
Q _{GS(th)}	pre-threshold gate- source charge	Fig. 12; Fig. 13	-	1.2	-	nC
Q _{GS(th-pl)}	post-threshold gate- source charge		-	0.5	-	nC
Q_{GD}	gate-drain charge		-	1.8	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I _D = 15 A; V _{DS} = 15 V; <u>Fig. 12</u> ; <u>Fig. 13</u>	-	2.2	-	V
C _{iss}	input capacitance	V _{DS} = 15 V; V _{GS} = 0 V; f = 1 MHz;	-	832	-	pF
C _{oss}	output capacitance	T _j = 25 °C; <u>Fig. 14</u>	-	587	-	pF
C _{rss}	reverse transfer capacitance		-	64	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 15 \text{ V}; R_L = 1 \Omega; V_{GS} = 4.5 \text{ V};$	-	9	-	ns
t _r	rise time	$R_{G(ext)} = 5 \Omega$	-	16.2	-	ns
t _{d(off)}	turn-off delay time		-	10.5	-	ns
t _f	fall time	1	-	10.9	-	ns

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Q _{oss}	output charge	$V_{GS} = 0 \text{ V}; V_{DS} = 15 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$		-	11.5	-	nC
Source-dra	in diode				'		
V_{SD}	source-drain voltage	$I_S = 10 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}; Fig. 15$		-	0.81	1.2	V
t _{rr}	reverse recovery time	$I_S = 15 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$		-	23.4	-	ns
Q _r	recovered charge	V _{DS} = 15 V; <u>Fig. 16</u>	[1]	-	12.6	-	nC
t _a	reverse recovery rise time			-	10.6	-	ns
t _b	reverse recovery fall time			-	12.8	-	ns
S	softness factor			-	1.2	-	

[1] includes capacitive recovery

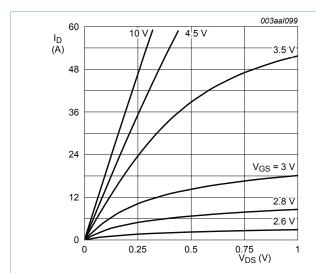


Fig. 7. Output characteristics; drain current as a function of drain-source voltage; typical values



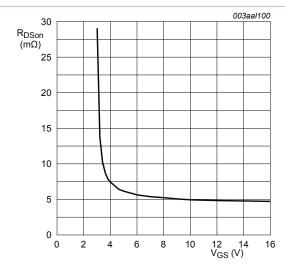


Fig. 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

$$T_j = 25$$
°C; $I_D = 15A$

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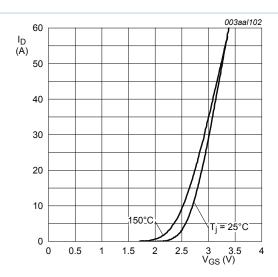


Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values

 $V_{DS} = 12V$

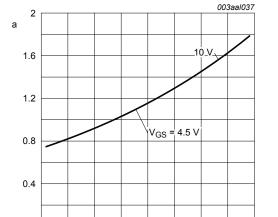


Fig. 11. Normalized drain-source on-state resistance factor as a function of junction temperature

30 60

0

-30

$$a = \frac{R_{DSon}}{R_{DSon (25^{\circ}C)}}$$

120 150 T_j (°C)

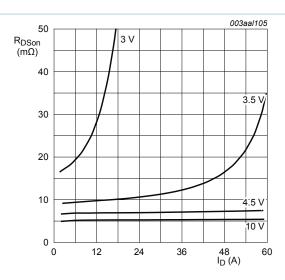


Fig. 10. Drain-source on-state resistance as a function of drain current; typical values

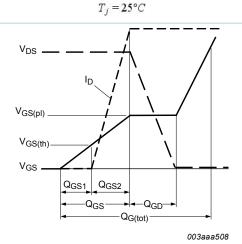


Fig. 12. Gate charge waveform definitions

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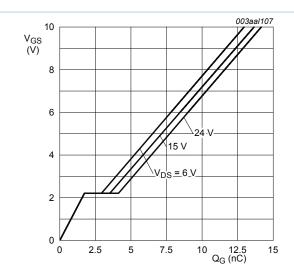


Fig. 13. Gate-source voltage as a function of gate charge; typical values

$$T_j = 25^{\circ}C; I_D = 15A$$

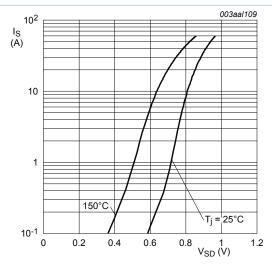


Fig. 15. Source current as a function of source-drain voltage; typical values

$$V_{GS} = 0V$$

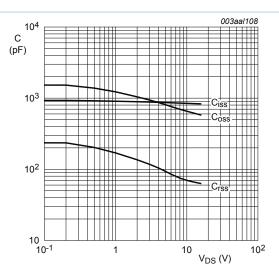


Fig. 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$$V_{GS} = \mathbf{0}V; f = \mathbf{1}MHz$$

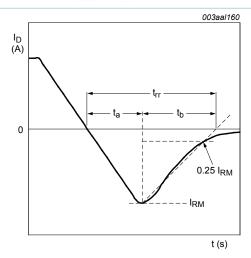
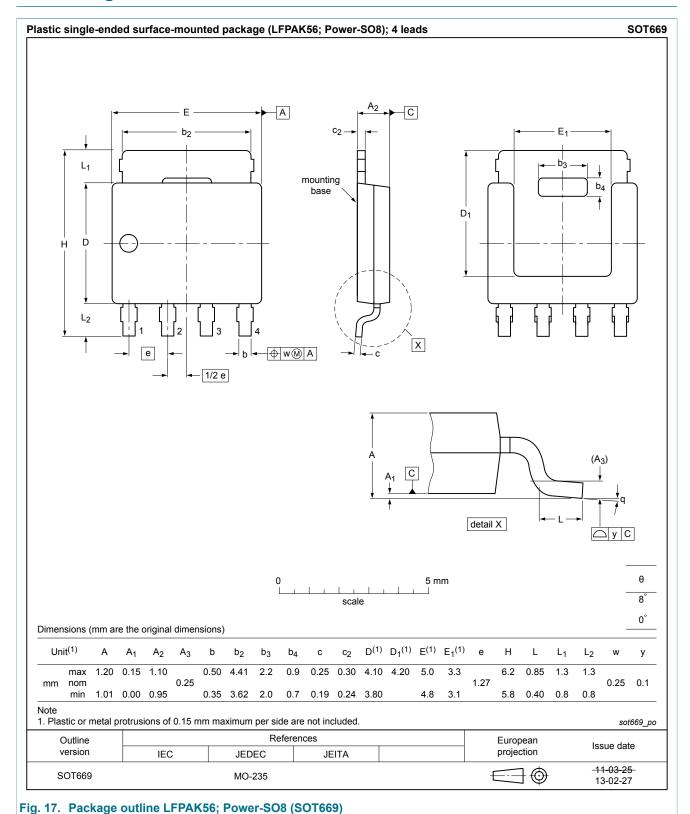


Fig. 16. Reverse recovery timing definition

11. Package outline



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